Nr.	Standard reference	English title
1	CEN/CLC/TR 17912:2023	Hyperloop systems - Standards Inventory and Roadmap
	, , , , , , , , , , , , , , , , , , , ,	IT security techniques - Competence requirements for information
2	EN ISO/IEC 19896-1:2023	security testers and evaluators - Part 1: Introduction, concepts and general
		requirements (ISO/IEC 19896-1:2018)
		IT security techniques - Competence requirements for information
3	EN ISO/IEC 19896-2:2023	security testers and evaluators - Part 2: Knowledge, skills and effectiveness
		,
<u> </u>		requirements for ISO/IEC 19790 testers (ISO/IEC 19896-2:2018)
4	EN ISO/IEC 19896-3:2023	IT security techniques - Competence requirements for information
		security testers and evaluators - Part 3: Knowledge, skills and effectiveness
		requirements for ISO/IEC 15408 evaluators (ISO/IEC 19896-3:2018)
5	EN IEC 60034-18-1:2023	Rotating electrical machines - Part 18-1: Functional evaluation of
<u> </u>		insulation systems - General guidelines
6	EN IEC 60216-6:2023	Electrical insulating materials - Thermal endurance properties - Part 6:
		Determination of thermal endurance indices (TI and RTI) of an insulating
		material using the fixed time frame method
7	EN IEC 60255-1:2023	Measuring relays and protection equipment - Part 1: Common
		requirements
8	EN IEC 60352-6:2023	Solderless connections - Part 6: Insulation piercing connections - General
	LIN IEC 00332-0.2023	requirements, test methods and practical guidance
	EN IEC 60601-2-43:2023	Medical electrical equipment - Part 2-43: Particular requirements for the
9		basic safety and essential performance of X-ray equipment for
		interventional procedures
10	EN IEC CO700 2-2022	Thyristor valves for high voltage direct current (HVDC) power transmission
10	EN IEC 60700-3:2023	- Part 3: Essential ratings (limiting values) and characteristics
11	EN IEC 60721-2-6:2023	Classification of environmental conditions - Part 2-6: Environmental
11		conditions appearing in nature - Earthquake vibration and shock
12	EN IEC 60747-16-7:2023	Semiconductor devices - Part 16-7: Microwave integrated circuits -
12		Attenuators
12	EN IEC 60747-16-8:2023	Semiconductor devices - Part 16-8: Microwave integrated circuits -
13		Limiters
1.1	EN IEC 60806:2023	Determination of the maximum symmetrical radiation field of X-ray tube
14		assemblies and X-ray source assemblies for medical diagnosis
4.5	EN IEC 60947-	
15	1:2021/AC:2023-01	Low-voltage switchgear and controlgear - Part 1: General rules
	•	Connectors for electrical and electronic equipment - Product requirements
16	EN IEC 61076-2-116:2023	- Part 2 -116: Detail specification for circular connectors size 15 with up to
		3+PE power contacts and auxiliary contacts, with bayonet-locking
	EN IEC 61869-	
17	99:2022/AC:2023-01	Instrument transformers - Part 99: Glossary
	EN IEC	Industrial communication networks - Installation of communication
18	61918:2018/A12:2023	networks in industrial premises
	01310.2010/A12.2023	Industrial-process measurement and control - Data structures and
	EN IEC 61987-31:2023	elements in process equipment catalogues - Part 31: List of Properties
19		(LOPs) of infrastructure devices for electronic data exchange - Generic
		structures
		Ultrasonics - Hydrophones - Part 3: Properties of hydrophones for
20	EN IEC 62127-3:2023	
		ultrasonic fields Ontical circuit heards - Pasis test and measurement presedures - Part 2.5:
	EN IEC 62496-2-5:2023	Optical circuit boards - Basic test and measurement procedures - Part 2-5:
		Flexibility test for flexible opto-electric circuits
22	EN IEC 62682:2023	Management of alarm systems for the process industries

23	EN IEC/IEEE 63195-1:2023	Assessment of power density of human exposure to radio frequency fields
		from wireless devices in close proximity to the head and body (frequency
		range of 6 GHz to 300 GHz) - Part 1: Measurement procedure
24	EN IEC/IEEE 63195-2:2023	Assessment of power density of human exposure to radio frequency fields
		from wireless devices in close proximity to the head and body (frequency
		range of 6 GHz to 300 GHz) - Part 2: Computational procedure
25	EN IEC 63245-2:2023	Spatial wireless power transfer based on multiple magnetic resonances -
		Part 2: Reference model
26	EN IEC 63364-1:2023	Semiconductor devices - Semiconductor devices for IoT system - Part 1:
		Test method of sound variation detection